The documentation and process conversion measures necessary to comply with this document shall be completed by 15 May 2015.

INCH-POUND

MIL-PRF-19500/406M <u>27 March 2015</u> SUPERSEDING MIL-PRF-19500/406L 3 March 2014

PERFORMANCE SPECIFICATION SHEET

* RECTIFIER, SEMICONDUCTOR DEVICE, SILICON, VOLTAGE REGULATOR, ENCAPSULATED THROUGH-HOLE AND SURFACE MOUNT PACKAGES, DEVICE TYPES 1N4460 THROUGH 1N4496, AND 1N6485 THROUGH 1N6491, QUALITY LEVELS JAN, JANTX, JANTXV, AND JANS

This specification is approved for use by all Departments and Agencies of the Department of Defense.

The requirements for acquiring the product described herein shall consist of this specification sheet and MIL-PRF-19500.

1. SCOPE

- * 1.1 Scope. This specification covers the performance requirements for micro-miniature 1.5 watt silicon, low leakage, voltage regulator diodes with tolerances of 5 percent, 2 percent, and 1 percent. Four levels of product assurance (JAN, JANTXV and JANS) are provided for each encapsulated device type as specified in MIL-PRF-19500.
- * 1.2 <u>Package Outlines</u>. The device packages for the encapsulated device types are as follows: DO-41 in accordance with figure 1, surface mount version US in accordance with figure 2, and surface mount version UM in accordance with figure 3.
 - 1.3 <u>Maximum ratings</u>. $T_{STG} = T_{J(max)} = -65^{\circ}C$ to +175°C. Maximum ratings are as shown in maximum and primary test ratings (see 3.6.2) herein and as follows:

P_T $T_L = +7$ $L = .37$ (9.53)	112ºC 5 inch at	P _T T _{EC} = +145°C	$P_{T(PCB1)}$ at $T_A = +55^{\circ}C$	$P_{T(PCB2)}$ $T_A = +55^{\circ}C$	P_T At $T_{SP} = +25^{\circ}C$	$R_{\theta JL}$ at L = .375 inch (9.52 mm)
1.5 W	/ (1)	1.5 W (2)	0.6 W (3)	1.5 W (4)	1.5 W (5)	42°C/W (6)

	5			Barometric pressure reduced
$R_{\theta JEC}$	$R_{\theta JSP}$	$R_{\theta JA(PCB1)}$	$R_{\theta JA(PCB2)}$	(high altitude operation)
20°C/W (7)	56°C/W (8)	200°C/W (3)	80°C/W (4)	8 mm Hg

Comments, suggestions, or questions on this document should be addressed to DLA Land and Maritime, ATTN: VAC, P.O. Box 3990, Columbus, OH 43218-3990, or emailed to Semiconductor@dla.mil . Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at https://assist.dla.mil .

AMSC N/A FSC 5961



1.3 Maximum ratings - continued.

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    (1) Derate: See figure 4 herein.
    (2) Derate: See figure 5 herein.
    (3) Derate: See figure 6 herein and 6.4.1 (PCB1) herein.
    (4) Derate: See figure 7 herein and 6.4.2 (PCB2) herein.
    (5) Derate: See figure 8 herein.
    (6) See figures 9 and 10 herein.
    (7) See figures 11 and 12 herein.
    (8) See figure 13 herein.
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- 1.4 <u>Primary electrical characteristics</u>. Primary electrical characteristics are as shown in maximum and primary test ratings (see 3.6.2) and as follows: 3.3 V dc \leq V_Z \leq 200 V dc (nominal).
 - a. 1N4460D through 1N4496D and 1N6485D through 1N6491D are 1 percent voltage tolerance.
 - b. 1N4460C through 1N4496C and 1N6485C through 1N6491C are 2 percent voltage tolerance.
 - c. 1N4460 through 1N4496 and 1N6485 through 1N6491 are 5 percent voltage tolerance.

 $R_{\rm B,II} = 42^{\circ} \text{C/W}$ (max) at L = .375 inch (9.52 mm) (non-surface mount).

 $R_{\theta,JEC} = 20^{\circ}C/W$ (max) (surface mount).

For thermal impedance curves, see figures 9, 10, 11, 12 and 13.

 $R_{AJSP} = 56^{\circ}C/W$ (max) (UM surface mount).

- * 1.5 Part or Identifying Number (PIN). The PIN is in accordance with MIL-PRF-19500, and as specified herein. See 6.5 for PIN construction example and 6.6 for a list of available PINs.
- * 1.5.1 JAN brand and quality level designators.
- * 1.5.1.1 <u>Encapsulated devices</u>. The quality level designators for encapsulated devices that are applicable for this specification sheet from the lowest to the highest level are as follows: "JAN", "JANTX", "JANTXV", and "JANS"
- * 1.5.2 <u>Device type</u>. The designation system for the device types of rectifiers covered by this specification sheet are as follows.
- * 1.5.2.1 <u>First number and first letter symbols</u>. The rectifiers of this specification sheet use the first number and letter symbols "1N".
- * 1.5.2.2 <u>Second number symbols</u>. The second number symbols for the rectifiers covered by this specification sheet are as follows: "4460" through "4496" and "6485" through "6491".
- * 1.5.3 Suffix symbols. The following suffix symbols are incorporated in the PIN as applicable.
- * 1.5.3.1 First suffix symbol. The first suffix symbol "C" indicates that the rectifier is a modified version of the approved device type.

* 1.5.3.2 Following suffix symbols. The following suffix symbols are incorporated in the PIN for this specification sheet:

	A blank second suffix symbol indicates a DO-41 through-hole mount package (see figure 1).
С	Indicates a 2 percent voltage tolerance.
D	Indicates a 1 percent voltage tolerance.
US	Indicates a surface mount package (see figure 2).
CUS	Indicates a surface mount package with a 2 percent voltage tolerance.
DUS	Indicates a surface mount package with a 1 percent voltage tolerance.
UM	Indicates a (see figure 3).

* 1.5.4 Lead finish. The lead finishes applicable to this specification sheet are listed on QML-19500.

2. APPLICABLE DOCUMENTS

2.1 <u>General</u>. The documents listed in this section are specified in sections 3 and 4 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3 and 4 of this specification, whether or not they are listed.

2.2 Government documents.

2.2.1 <u>Specifications, standards, and handbooks</u>. The following specifications, standards, and handbooks form a part of this document to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATIONS

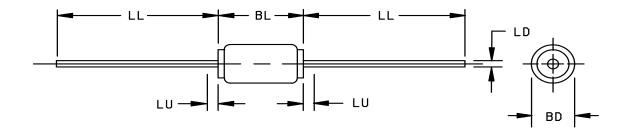
MIL-PRF-19500 - Semiconductor Devices, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-750 - Test Methods for Semiconductor Devices.

(Copies of these documents are available online at http://quicksearch.dla.mil.)

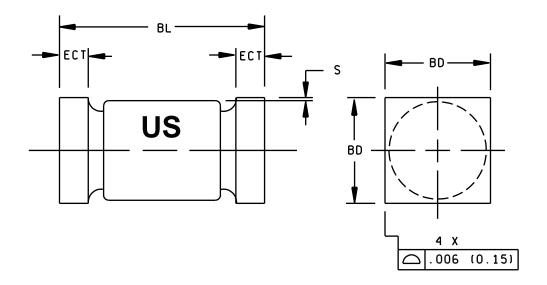
2.3 <u>Order of precedence</u>. Unless otherwise noted herein or in the contract, in the event of a conflict between the text of this document and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.



Ltr	Inches		Millimeters		Notes
	Min	Max	Min	Max	
BD	.060 .085		1.52	2.16	3
BL	.106 .160		2.69	4.06	3
LD	.028 .032 0.71		0.81		
LL	.800 1.300 20.3		20.32	33.02	
LU	.050			1.27	4

- Dimensions are in inches.
 Millimeters are given for general information only.
 Package contour optional with BD and length BL. Heat slugs, if any, shall be included within this cylinder length but shall not be subject to minimum limit of BD.
- 4. The specified lead diameters apply in the zone between .050 inch (1.27 mm) from the diode body and the end of the lead.
- 5. In accordance with ASME Y14.5M, diameters are equivalent to Φx symbology.

FIGURE 1. Physical dimensions of non-surface mount device (DO-41).

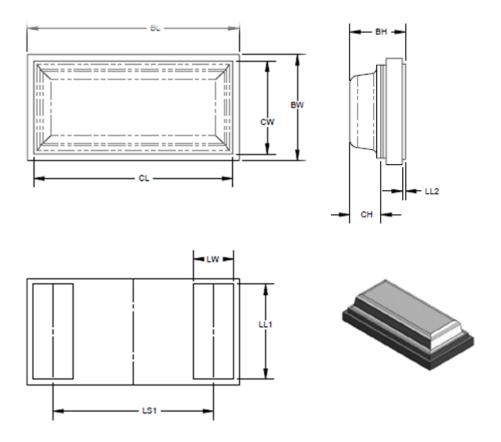


	Dimensions					
Ltr	Inc	hes	Millim	neters		
	Min	Max	Min	Max		
BD	.091	.103	2.31	2.62		
BL	.168	.200	4.28	5.08		
ECT	.019	.028	0.48	0.71		
S	.003		0.08			

- 1. Dimensions are in inches.

- Millimeters are given for general information only.
 Dimensions are pre-solder dip.
 In accordance with ASME Y14.5M, diameters are equivalent to Φx symbology.

FIGURE 2. Physical dimensions of surface mount device (US).



	Dimensions					
Ltr	Incl	hes	Millimeters			
	Min	Max	Min	Max		
BL	.192	.202	4.877	5.131		
BW	.093	.104	2.362	2.642		
BH	.044 .062		1.117 1.574			
LW	.030	.044	.762	1.118		
LL1	.083	.094	2.108	2.387		
LL2	.0024	.0035	.0609	.0889		
LS1	.144	.144 .155		3.937		
CH	.020	.034	.508	.864		
CL	.179	.191	4.546	4.851		
CW	.081	.093	2.057	2.362		

FIGURE 3. Physical dimensions of DPC surface mount device, UM.

3. REQUIREMENTS

- 3.1 General. The individual item requirements shall be as specified in MIL-PRF-19500 and as modified herein.
- 3.2 Qualification. Devices furnished under this specification shall be products that are authorized by the qualifying activity for listing on the applicable qualified manufacturer's list (QML) before contract award (see 4.2 and 6.3).
- 3.3 <u>Abbreviations, symbols, and definitions</u>. The abbreviations, symbols, and definitions used herein shall be as specified in MIL-PRF-19500, and as follows:
 - EC End-cap.
 - IZT Zener test current.
 - US Surface mount case outline, square end-cap.
 - UM Surface mount case outline, DPC package.
 - ZK Knee impedance.
 - α_{VZ} Temperature coefficient.
- 3.4 <u>Interface and physical dimensions</u>. The interface and physical dimensions shall be as specified in <u>MIL-PRF-19500</u>, and herein. The device package styles shall be as follows: DO-41 in accordance with figure 1, surface mount version US in accordance with figure 2, and surface mount version UM in accordance with figure 3.
- 3.4.1 <u>Diode construction (except UM version)</u>. All devices shall be metallurgically bonded, double plug construction, thermally matched, and non-cavity in accordance with the requirements of MIL-PRF-19500. US version devices shall be structurally identical to the axial leaded type except for lead attachment.
- 3.4.1.1 <u>Metallurgical bond for diodes with V_Z greater than 6.8 V dc (except UM version)</u>. These devices shall be constructed utilizing category I metallurgical bonds for diodes with V_Z greater than 6.8 V dc as defined in MIL-PRF-19500.
- 3.4.1.2 <u>Metallurgical bond for diodes with V_Z less than or equal to 6.8 V dc (except UM version)</u>. These devices shall be constructed utilizing category I or category III metallurgical bonds as defined in MIL–PRF–19500.
- 3.4.2 <u>Lead finish</u>. Lead finish shall be solderable in accordance with MIL-PRF-19500, MIL-STD-750, and herein. When solder alloy is used for lead finish the maximum lead temperature shall be 175°C max. Where a choice of lead finish is desired, it shall be specified in the acquisition document (see 6.2).
 - 3.5 Marking.
- * 3.5.1 Through hole mount packages. Marking shall be in accordance with MIL-PRF-19500.
- * 3.5.2 <u>Surface mount packages(US)</u>. Marking shall be in accordance with <u>MIL-PRF-19500</u>, except that marking on the US devices shall be marked with a cathode band as a minimum; or a minimum of three evenly spaced contrasting color dots around the periphery of the cathode end may be used. At the option of the manufacturer, US devices may include laser marking on an end-cap, to include part number and lot date code for all levels. JANS devices which are laser marked shall also include serialization. The prefixes JAN, JANTXV, or JANS may be abbreviated as J, JX, JV, or JS, respectively. (For example: The part number may be reduced to JS4460). All device marking, except for polarity and serial numbers, shall also appear on the unit package used as the initial protection for delivery.
- * 3.5.3 <u>Surface mount packages (UM)</u>. Marking shall be in accordance with <u>MIL-PRF-19500</u>, except that marking on the UM version devices only, all marking shall be on lid to include part number, date code, serial number and cathode end.
 - 3.5.4 <u>Polarity</u>. The polarity of all types shall be indicated with a contrasting color band to denote the cathode end. For UM devices, a line on the lid shall denote the cathode end.

- 3.6 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in 1.3, 1.4, table I and table II herein.
- 3.6.1 <u>Selection of tighter tolerance devices</u>. The C and D suffix devices shall be selected from JAN, JANTX, JANTXV, or JANS devices, which have successfully completed all applicable screening, and groups A, B, and C testing as ± 5 percent tolerance devices. All sublots of C and D suffix devices shall pass table I, subgroup 2, at tightened tolerances. Tighter tolerances for mounting clip temperature shall be maintained for reference purposes to establish correlation. For C and D tolerance levels, $T_L = 25^{\circ}C$, $+1^{\circ}C$, $-3^{\circ}C$ at .375 inch (9.53 mm) from body, or zero inches for surface mount devices or equivalent.
- 3.6.2 <u>Maximum and primary test ratings</u>. Maximum and primary test ratings for voltage regulator diodes are specified in table III herein.
- 3.7 <u>Workmanship</u>. Devices shall be processed in such a manner as to be uniform in quality and shall be free from other defects that will affect life, serviceability, or appearance.
 - 4. VERIFICATION
 - 4.1 Classification of inspections. The inspection requirements specified herein are classified as follows:
 - a. Qualification inspection (see 4.2).
 - b. Screening (see 4.3).
 - c. Conformance inspection (see 4.4).
- 4.2 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-19500, and as specified herein.
- 4.2.1 <u>Group E qualification</u>. Group E inspection shall be performed for qualification or requalification only. In case qualification was awarded to a prior revision of the specification sheet that did not request the performance of table II tests, the tests specified in table II herein that were not performed in the prior revision shall be performed on the first inspection lot of this revision to maintain qualification.

* 4.3 <u>Screening (quality levels JANTX, JANTXV and JANS only)</u>. Screening of packaged devices shall be in accordance with table E-IV of MIL-PRF-19500, and as specified herein. The following measurements shall be made in accordance with table I herein. Devices that exceed the limits of table I herein shall not be acceptable.

Screen	Measurements				
Screen	JANS level	JANTX and JANTXV levels			
3b (1) 3c	Not applicable Thermal impedance, see 4.3.1	Not applicable Thermal impedance, see 4.3.1			
9	I _{R1} and V _Z (1N4466 thru 1N4496 only)	Not applicable			
10	Required for device > 10 V dc.	Not applicable			
11	I_{R1} and V_Z , $\Delta I_{R1} \le \pm 100$ percent of initial reading or 50 nA, whichever is greater. $\Delta V_Z \le \pm 2$ percent of initial reading (2)	I_{R1} and V_Z			
12	Required see 4.3.2	Required see 4.3.2			
13	Scope display see 4.5.7 Subgroups 2 and 3 of table I herein; ΔI_{R1} (max) $\leq \pm 100$ percent of initial reading or 25 percent of column 12 in table III (1N6485 – 1N4466); 50 nA (1N4467 – 1N4496), whichever is greater; $\Delta V_Z \leq \pm 2$ percent of initial reading	Subgroup 2 of table I herein; ΔI_{R1} (max) $\leq \pm 100$ percent of initial reading or 25 percent of column 12 in table III (1N6485 – 1N4466); 50 nA (1N4467 – 1N4496), whichever is greater; $\Delta V_Z \leq \pm 2$ percent of initial reading			

- (1) Shall be performed any time after temperature cycling, screen 3a; JANTX and JANTXV levels do not need to be repeated in screening requirements.
- 4.3.1 <u>Thermal impedance</u>. The thermal impedance measurements shall be performed in accordance with method 3101 or 4081 of MIL-STD-750, as applicable, using the guidelines in that method for determining I_M , I_H , t_H , t_{SW} (V_C and V_H where appropriate). See table II, group E, subgroup 4 herein.
- 4.3.2 <u>Free air power burn-in conditions</u>. Power burn-in conditions are as follows (see 4.5.6): $T_A = 75^{\circ}\text{C}$ maximum. Test conditions in accordance with method 1038 of MIL-STD-750, condition B. Adjust I_Z or T_A to achieve the required T_J , and $I_{Z(min)}$ shall be ≥ 50 percent of column 8 of table III. $T_J = 135^{\circ}\text{C}$ minimum. With approval of the qualifying activity and preparing activity, alternate burn-in criteria (hours, bias conditions, T_J , mounting conditions) may be used for JANTX and JANTXV quality levels. A justification demonstrating equivalence is required. In addition, the manufacturing site's burn-in data and performance history will be essential criteria for burn-in modification approval.

- 4.4 <u>Conformance inspection</u>. Conformance inspection shall be in accordance with MIL-PRF-19500 and as specified herein.
 - 4.4.1 Group A inspection. Group A inspection shall be in accordance with MIL-PRF-19500 and table I herein.
- * 4.4.2 Group B inspection.
- * 4.4.2.1 Quality level JANS, table E-VIA of MIL-PRF-19500. Group B inspection shall be conducted in accordance with the tests and conditions specified for subgroup testing in table E-VIA (JANS) of MIL-PRF-19500

Subgroup	Method	Condition
В3	1056	0° C to +100°C, 25 cycles, n = 22, c = 0.
В3	1051	-55°C to +175°C, 100 cycles, n = 22, c = 0.
В3	1071	Fine leak and gross leak shall be performed for UM version devices. Test condition E shall be performed for non-UM version devices. NOTE: For non-transparent devices, hermetic seal may be performed after electrical measurements.
B4	1037	I_Z = 80 percent of column 8 of table III at T_A = room ambient as defined in the general requirements of 4.5 of MIL-STD-750; for 2,000 cycles.
B5	1027	I_Z = 50 percent of column 8 of table III minimum; adjust either T_A , and or I_Z to achieve T_J minimum. Temporary leads may be added for surface mount devices, n = 45, c = 0.
		Option 1: $T_A = +100^{\circ}\text{C}$ max; $T_J = +275^{\circ}\text{C}$ minimum; $t = 96$ hours. $n = 22$, $c = 0$. Option 2: $T_A = +100^{\circ}\text{C}$ max; $T_J = +175^{\circ}\text{C}$ minimum; $t = 1,000$ hours. $n = 45$, $c = 0$.

* 4.4.2.2 Quality levels JAN, JANTX, and JANTXV of MIL-PRF-19500. Group B inspection shall be conducted in accordance with the tests and conditions specified for subgroup testing in table E-VIB (JAN, JANTX, and JANTXV) of MIL-PRF-19500.

<u>Subgroup</u>	<u>Method</u>	<u>Condition</u>
B2	1056	0° C to +100°C, 10 cycles, n = 22, c = 0.
B2	1051	-55°C to +175°C, 25, cycles, n = 22, c = 0.
B2	1071	Fine leak and gross leak shall be performed for UM version devices. Test condition E shall be performed for non-UM version devices. NOTE: For non-transparent devices, hermetic seal may be performed after electrical measurements.
В3	1027	$I_{Z(min)}$ = 50 percent of column 8 of table III minimum. Adjust either T_A , I_Z , or both to achieve T_J = 150°C min (see 4.5.6).

4.4.3 <u>Group C inspection</u>. Group C inspection shall be conducted in accordance with the conditions specified for subgroup testing in appendix E, table E-VII of MIL-PRF-19500 and herein. Delta requirements shall be in accordance with the applicable inspections of table I, subgroup 2 herein. Z_{θJX} is an end-point for these subgroups: C2 and C6 (JAN, JANTX, and JANTXV product levels only).

4.4.3.1 Group C inspection, table E-VII of MIL-PRF-19500.

Subgroup	Method	Condition
C2	1056	0° C to +100°C, 15 cycles, n = 22, c = 0.
C2	1051	-55°C to +175°C, 25 cycles, n = 22, c = 0.
C2	1071	Fine leak and gross leak shall be performed for UM suffix devices. Test condition E shall be performed for non-UM suffix devices. NOTE: For non-transparent devices, hermetic seal may be performed after electrical measurements.
C2	2036	Tension - test condition A; 10 lbs; t = 15 s ± 3 s. Lead fatigue - Test condition E. NOTE: Not applicable to US and UM suffix devices.
C2	2038	US, URS suffix devices - Tension: Condition B, 10 pounds, t = 15s.
C5	4081	R_{BJL} and R_{BJEC} see 1.3 and 4.3.2 herein.
C6	1026	$I_{Z(min)}$ = 50 percent of column 8 of table III minimum. Adjust I_Z or T_A to achieve T_J = 150°C min (see 4.5.6).
C7	1018	Not applicable, except for UM suffix devices.
C8	4071	Temperature coefficient for JAN, JANTX, and JANTXV only; I_Z = column 5 of table III; T_{A1} = +25°C ±5°C; T_{A2} = +125°C ±5°C; limit = column 13 of table III (see 4.5.3), n = 22, c = 0.

- * 4.4.4 <u>Group E inspection</u>. Group E inspection shall be conducted in accordance with the conditions specified for subgroup testing in table E-IX of MIL-PRF-19500 and as specified in table II herein.
 - 4.5 Methods of inspection. Methods of inspection shall be as specified in the appropriate tables and as follows.
 - 4.5.1 Voltage regulation ($V_{Z(reg)}$). The breakdown voltage shall be measured at I_Z = 10 percent of column 8 of table III and at I_Z = 50 percent of column 8 of table III. The difference between these voltages shall then be determined and shall not exceed column 9 of table III. The voltage measurement at I_Z = 10 percent of column 8 of table III shall be a pulse measurement in accordance with 4.5.5. The measurement at I_Z = 50 percent of column 8 of table III shall be made after current has been applied for 30 ±3 seconds. For this time interval, the device shall be suspended in free air by its leads with mounting clips with inside edge .375 inch (9.53 mm) from the body, and the point of connection shall be maintained at a temperature of +25°C, +8°C, -2°C. No forced air across the device shall be permitted. US suffix devices shall be mounted with the end-caps maintained at +25°C, +8°C, -2°C. For JANHC and JANKC, the die shall be stabilized at +25°C and the test shall be performed utilizing pulse conditions. The ΔV_Z measurement may be performed after a shorter time interval following application of the test current if correlation can be established to the satisfaction of the qualifying activity.

- 4.5.2 Surge current (I_{ZSM}). The peak currents specified in column 10 of table III shall be applied in the reverse direction and shall be superimposed on the current (I_Z = column 5 of table III) a total of five surges at 1 minute intervals. Each individual surge shall be at one-half square wave pulse of 8.3 millisecond duration or an equivalent sine wave with the same effective (rms) current.
- 4.5.3 <u>Temperature coefficient of regulator voltage (α_{VZ})</u>. The device shall be temperature stabilized with current applied prior to reading regulator voltage at the specified ambient temperature.
- 4.5.4 Regulator voltage. The test current (column 5 of table III) shall be applied until thermal equilibrium is attained prior to reading the regulator voltage. For this test, the diode shall be suspended by its leads (non-surface mount) with mounting clips whose inside edge is located at $.375 \pm .010$ inch $(9.53 \pm 0.25 \text{ mm})$ from the body and the lead temperature at inside edge of the mounting clips shall be maintained at a temperature of $+23^{\circ}$ C to $+33^{\circ}$ C. For surface mount diodes, the diode shall be suspended by the end-caps with the temperature of the end-caps being maintained at $+23^{\circ}$ C to $+33^{\circ}$ C. This measurement may be performed after a shorter time following application of the test current than that which provides thermal equilibrium if correlation to stabilized readings can be established to the satisfaction of the qualifying activity.
- 4.5.5 <u>Pulse measurements</u>. Conditions for pulse measurements shall be as specified in section 4 of MIL-STD-750.
- 4.5.6 <u>Free air power burn-in and life tests</u>. The use of a current limiting or ballast resistor is permitted provided that each DUT still sees at least $I_{Z(min)}$ described in 4.3.2 and that the minimum applied voltage, where applicable, is maintained through-out the burn-in period. Use method 3100 of MIL-STD-750 to measure T_J.
- $4.5.7 \, \underline{\text{Scope display evaluation}}$. Scope display evaluation shall be sharp and stable in accordance with method 4023 of $\underline{\text{MIL-STD-750}}$. Scope display may be performed on automatic test equipment (ATE) for screening only, with the approval of the qualifying activity. Scope display in table I, subgroup 4 shall be performed on a scope. The reverse current (I_{BR}) over the knee shall be 500 μ A peak.
- 4.5.7.1 <u>Scope display option</u>. At the suppliers option, 100-percent scope display evaluation may be discontinued after three consecutive lots are 100-percent tested with zero failures. Any table I failure shall require 100-percent scope display to be re-invoked.

TABLE I. Group A inspection.

		MIL-STD-750	0 1 1	Lim	its <u>2</u> /	11.7
Inspection 1/	Method	Conditions	Symbol	Min	Max	Unit
Subgroup 1						
Visual and mechanical examination	2071					
Subgroup 2						
Thermal impedance	3101	See 4.3.1	$Z_{\theta JX}$			°C/W
Forward voltage	4011	I _F = 200 mA dc	V _{F1}		1.0	V dc
Forward voltage	4011	I _F = 1 A dc	V_{F2}		1.5	V dc
Reverse current leakage	4016	DC method; V _R = column 11 of table III	I _{R1}		Column 12	μA dc
Regulator voltage	4022	I _Z = column 5 of table III (see 4.5.4)	Vz	Column 3 -5, -2, -1 percent	Column 4 +5, +2, +1 percent	V dc
Subgroup 3						
High temperature operation		T _A = +150°C				
Reverse current leakage	4016	DC method; V _R = column 11 of table III	I _{R2}		Column 15	μA dc
Subgroup 4						
Small-signal reverse breakdown impedance	4051	I _Z = column 5 of table III I _{sig} = 10 percent I _Z	Z_Z		Column 6	ohms
Knee impedance	4051	I_{ZK} = column 14 of table III I_{sig} = 10 percent I_{ZK}	Z _{ZK}		Column 7	ohms
Scope display	4023	See 4.5.7				
Subgroup 5						
Not applicable						
Subgroup 6						
Surge current	4066	I _{ZSM} = column 10 of table III at T _A +25°C (see 4.5.2)	I _{ZSM}		Column 10	А
End-point electrical measurements		See table I, subgroup 2 except Z _{θJX}				

See footnotes at end of table.

TABLE I. Group A inspection - Continued.

Inapartian 1/		MIL-PRF-19500	Symbol	Lim	its <u>2</u> /	Unit
Inspection 1/	Method	Conditions	Symbol	Min	Max	Offic
Subgroup 7 Voltage regulation		See 4.5.4	V _{Z(reg)}		Column 9	V dc
Temperature coefficient of regulator voltage	4071	JANS level only $I_Z = \text{column 5 of table III}$ $T_{A1} = +25^{\circ}\text{C} \pm 5^{\circ}\text{C},$ $T_{A2} = 120^{\circ}\text{C} \le T_2 \le 130^{\circ}\text{C}$	$\alpha_{ m VZ}$		Column 13	%/°C

^{1/} For sampling plan, see MIL-PRF-19500. 2/ Column references are to table III.

TABLE II. Group E inspection (all quality levels).

Inspection 1/		MIL-STD-750	Sampling	
inspection <u>i</u> /	Method	Method Conditions		
Subgroup 1			22 devices c = 0	
Thermal shock	1056	Test condition D, 20 cycles, except low temperature shall be achieved using liquid nitrogen (-195°C). Perform a visual inspection for cracked glass.		
Temp cycling	1051	-65°C to +175°C, 500 cycles.		
Hermetic seal Fine leak Gross leak	1071	Fine leak is applicable for UM version devices only.		
Electrical measurements		See table I, subgroup 2.		
Subgroup 2			22 devices c = 0	
Steady-state intermittent operating life	1037	$I_Z = I_{Z2}$ (column 8 of table III) at T_A = room ambient for 10,000 cycles. No forced air cooling on the device shall be permitted.	C = 0	
Electrical measurements		See table I, subgroup 2.		
Subgroup 4				
Thermal impedance curves		See MIL-PRF-19500.	Sample size N/A	
Subgroups 5 and 6			IN/A	
Not applicable				
Subgroup 8			45 devices c=0	
Resistance to glass cracking (Not applicable for UM devices).	1057	Condition B. Step stress to destruction by increased cycles or up to a maximum of 25 cycles.	C=U	

 $[\]underline{1}/$ A separate sample may be pulled for each test.

TABLE III. Electrical characteristics and test conditions (all case outlines).

Col 1	Col 2	Col 3	Col 4	Col 5	Col 6	Col 7	Col 8	Col 9	Col 10	Col 11	Col 12	Col 13	Col 14	Col 15
Device type	V _Z Nom	V _Z Min <u>1</u> / <u>2</u> /	V _Z Max <u>1</u> / <u>2</u> /	I _Z test current T _A = +25°C	Z _Z Imped- ance	ZK Knee imped- ance	$I_{Z(max)}$ dc current $T_{A}=$ +25°C $\underline{3}/$	V _{Z(reg)} Voltage regula-tion 4/	I _{ZSM} T _A = +25°C <u>5</u> /	V _R Reverse voltage	I _R Reverse current dc I _{R1}	α _{VZ} Temper- ature coefficient <u>6</u> /	I _{ZK} Test current	I _R T _A = +150°C I _{R2}
	V	V	V	mA	Ω	Ω	mA	V	Α	V	μΑ	%/°C	mΑ	μΑ
1N6485	3.3	3.14	3.46	76	10	400	433	0.9	4.2	1.0	50.00	075	1.00	500
1N6486	3.6	3.42	3.78	69	10	400	397	0.8	3.9	1.0	50.00	070	1.00	200
1N6487	3.9	3.71	4.09	64	9	400	366	.75	3.6	1.0	35.00	060	1.00	100
1N6488	4.3	4.09	4.51	58	9	400	332	.70	3.3	1.0	5.00	050	1.00	100
1N6489	4.7	4.47	4.93	53	8	500	304	.60	3.0	1.0	4.00	±.025	1.00	100
1N6490	5.1	4.85	5.35	49	7	500	280	.50	2.7	1.0	1.00	±.030	1.00	100
1N6491	5.6	5.32	5.88	45	5	600	255	.40	2.5	2.0	.50	±.040	1.00	100
1N4460	6.2	5.89	6.51	40	4	200	230	.35	2.3	3.72	10.00	+.050	1.00	50
1N4461	6.8	6.46	7.14	37	2.5	200	210	.30	2.1	4.08	5.00	+.057	1.00	20
1N4462	.5	7.13	7.87	34	2.5	400	191	.35	1.9	4.50	1.00	+.061	0.50	10
1N4463	8.2	7.79	8.61	31	3.0	400	174	.40	1.7	4.92	0.50	+.065	0.50	5
1N4464	9.1	8.65	9.55	28	4.0	500	157	.45	1.6	5.46	0.30	+.068	0.50	3
1N4465	10	9.50	10.50	25	5.0	500	143	.50	1.4	8.0	0.30	+.071	0.25	3
1N4466	11	10.45	11.55	23	6.0	550	130	.55	1.3	8.8	0.30	+.073	0.25	2
1N4467	12	11.40	12.60	21	7.0	550	119	.60	1.2	9.6	0.20	+.076	0.25	2
1N4468	13	12.35	13.65	19	8.0	550	110	.65	1.1	10.4	.05	+.079	0.25	2
1N4469	15	14.25	15.75	17	9.0	600	95	.75	.95	12.0	.05	+.082	0.25	2
1N4470	16	15.20	16.80	15.5	10.0	600	90	.80	.90	12.8	.05	+.083	0.25	2
1N4471	18	17.10	18.90	14	11.0	650	79	.83	.79	14.4	.05	+.085	0.25	2
1N4472	20	19.00	21.00	12.5	12.0	650	71	.95	.71	16.0	.05	+.086	0.25	2
1N4473	22	20.90	23.10	11.5	14	650	65	1.0	.65	17.6	.05	+.087	0.25	2
1N4474	24	22.80	25.20	10.5	16	700	60	1.1	.60	19.2	.05	+.088	0.25	2
1N4475	27	25.70	28.30	9.5	18	700	53	1.3	.53	21.6	.05	+.090	0.25	2
1N4476	30	28.50	31.50	8.5	20	750	48	1.4	.48	24.0	.05	+.091	0.25	2
1N4477	33	31.40	34.60	7.5	25	800	43	1.5	.43	26.4	.05	+.092	0.25	2

TABLE III. <u>Electrical characteristics and test conditions (all case outlines)</u> - Continued.

Col 1	Col 2	Col 3	Col 4	Col 5	Col 6	Col 7	Col 8	Col 9	Col 10	Col 11	Col 12	Col 13	Col 14	Col 15
Device type	V _Z Nom	V _Z Min <u>1</u> / <u>2</u> /	V _Z Max <u>1</u> / <u>2</u> /	IZ test current T _A = +25°C	Z _Z Imped- ance	ZK Knee imped- ance	I _{Z(max)} dc current T _A = +25°C 3/	V _{Z(reg)} Voltage regulation 4/	I _{ZSM} T _A = +25°C <u>5</u> /	V _R Reverse voltage	I _R Reverse current dc I _{R1}	α _{VZ} Temper- ature coeffici- ent <u>6</u> /	I _{ZK} Test current	I _R T _A = +150°C I _{R2}
	V	V	V	mA	Ω	Ω	mA	V	Α	V	μΑ	%/°C	mA	μΑ
1N4478	36	34.2	37.8	7.0	27	850	40	1.7	.40	28.8	.05	+.093	0.25	2
1N4479	39	37.1	40.9	6.5	30	900	37	1.8	.37	31.2	.05	+.094	0.25	2
1N4480	43	40.9	45.1	6.0	40	950	33	1.9	.33	34.4	.05	+.095	0.25	2
1N4481	47	44.7	49.3	5.5	50	1000	30	2.1	.30	37.6	.05	+.095	0.25	2
1N4482	51	48.5	53.5	5.0	60	1100	28	2.3	.28	40.8	.05	+.096	0.25	2
1N4483	56	53.2	58.8	4.5	70	1300	26	2.5	.26	44.8	.25	+.096	0.25	10
1N4484	62	58.9	65.1	4.0	80	1500	23	2.7	.23	49.6	.25	+.097	0.25	10
1N4485	68	64.6	71.4	3.7	100	1700	21	3.0	.21	54.4	.25	+.097	0.25	10
1N4486	75	71.3	78.7	3.3	130	2000	19	3.3	.19	60.0	.25	+.098	0.25	10
1N4487	82	77.9	86.1	3.0	160	2500	17	3.6	.17	65.6	.25	+.098	0.25	10
1N4488	91	86.5	95.5	2.8	200	3000	16	4.0	.16	72.8	.25	+.099	0.25	10
1N4489	100	95.0	105.0	2.5	250	3100	14	4.4	.14	80.0	.25	+.100	0.25	10
1N4490	110	104.5	115.5	2.3	300	4000	13	5.0	.13	88.0	.25	+.100	0.25	10
1N4491	120	114.0	126.0	2.0	400	4500	12	5.5	.12	96.0	.25	+.100	0.25	10
1N4492	130	123.5	136.5	1.9	500	5000	11	6.0	.11	104	.25	+.100	0.25	10
1N4493	150	142.5	157.5	1.7	700	6000	9.5	7.0	.095	120	.25	+.100	0.25	10
1N4494	160	152	168	1.6	1000	6500	8.9	8.0	.089	128	.25	+.100	0.25	10
1N4495	180	171	189	1.4	1300	7000	7.9	10.0	.079	144	.25	+.100	0.25	10
1N4496	200	190	210	1.2	1500	8000	7.2	12.0	.072	160	.25	+.100	0.25	10

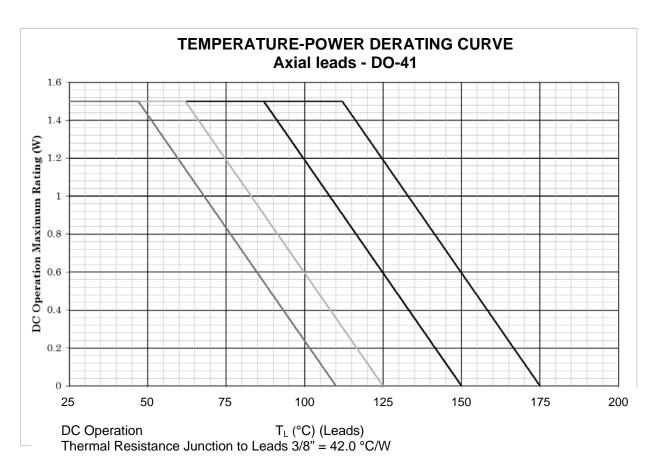
^{1/} See 4.5.5. Voltages shown are for 5 percent tolerance devices. Voltages for 2 and 1 percent tolerances devices shall be calculated accordingly.

^{2/ 1}N4460D through 1N4496D and 1N6485D through 1N6491D are 1 percent voltage tolerance.

¹N4460C through 1N4496C and 1N6485C through 1N6491C are 2 percent voltage tolerance.

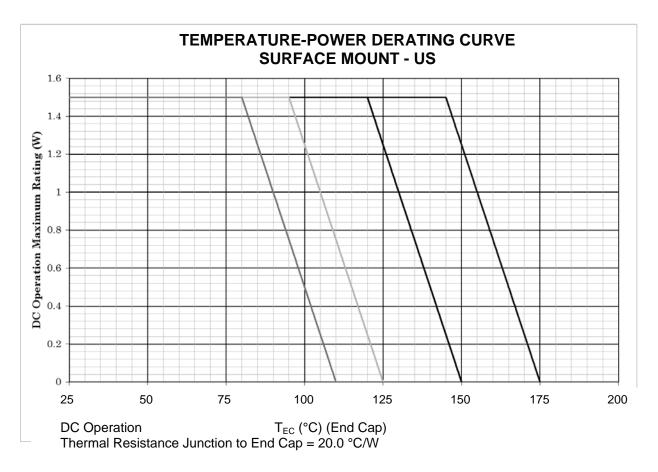
¹N4460 through 1N4496 and 1N6485 through 1N6491 are 5 percent voltage tolerance.

^{3/} See 1.3 for P_T temperature conditions for lead, end-cap and UM package where I_{ZM} is applicable. 4/ See 4.5.1. 5/ See 4.5.2. 6/ See 4.5.3.



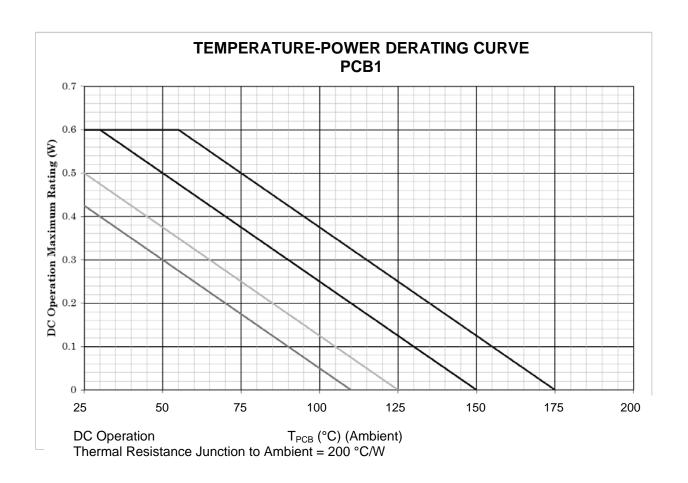
- 1. All devices are capable of operating at $\leq T_J$ specified on this curve. Any parallel line to this curve will intersect the appropriate power for the desired maximum T_J allowed.
- 2. Derate design curve constrained by the maximum junction temperature ($T_J \le 175$ °C) and power rating specified. (See 1.3 herein.)
- 3. Derate design curve chosen at $T_J \le 150$ °C, where the maximum temperature of electrical test is performed.
- Derate design curves chosen at T_J ≤ 125°C, and 110°C to show power rating where most users want to limit T_J in their application.

FIGURE 4. Temperature/power derating curve.



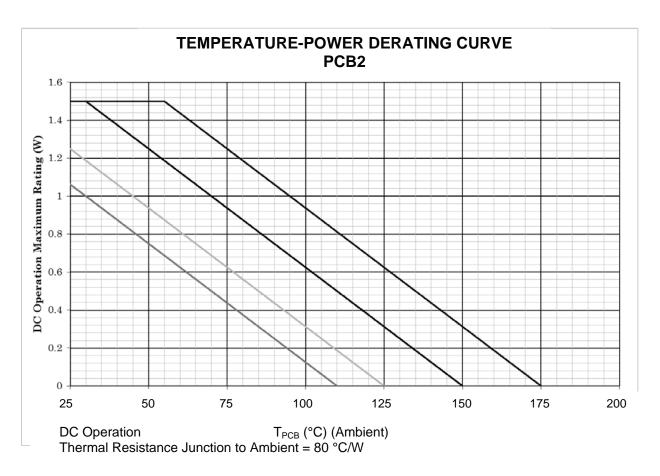
- 1. All devices are capable of operating at $\leq T_J$ specified on this curve. Any parallel line to this curve will intersect the appropriate power for the desired maximum T_J allowed.
- 2. Derate design curve constrained by the maximum junction temperature ($T_J \le 175$ °C) and power rating specified. (See 1.3 herein.)
- 3. Derate design curve chosen at $T_J \le 150$ °C, where the maximum temperature of electrical test is performed.
- Derate design curves chosen at T_J ≤ 125°C, and 110°C to show power rating where most users want to limit T_J in their application.

FIGURE 5. Temperature/power derating curve.



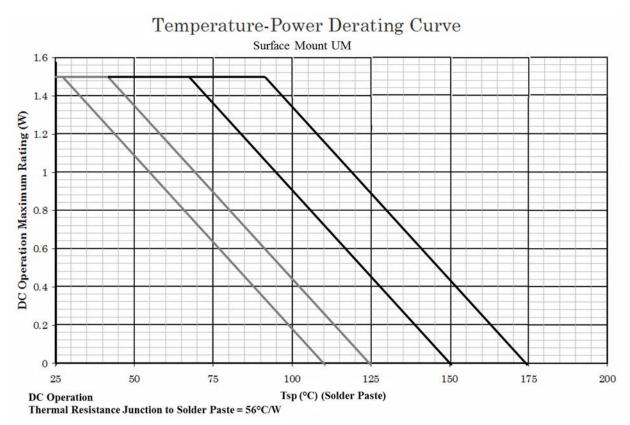
- 1. All devices are capable of operating at ≤ T_J specified on this curve. Any parallel line to this curve will intersect the appropriate power for the desired maximum T_J allowed.
- 2. Derate design curve constrained by the maximum junction temperature ($T_J \le 175$ °C) and power rating specified. (See 1.3 herein.)
- 3. Derate design curve chosen at $T_J \le 150$ °C, where the maximum temperature of electrical test is performed.
- 4. Derate design curves chosen at $T_J \le 125$ °C, and 110°C to show power rating where most users want to limit T_J in their application.

FIGURE 6. Temperature/power derating curve.



- 1. All devices are capable of operating at $\leq T_J$ specified on this curve. Any parallel line to this curve will intersect the appropriate power for the desired maximum T_J allowed.
- 2. Derate design curve constrained by the maximum junction temperature ($T_J \le 175$ °C) and power rating specified. (See 1.3 herein.)
- 3. Derate design curve chosen at $T_J \le 150$ °C, where the maximum temperature of electrical test is performed.
- 4. Derate design curves chosen at $T_J \le 125$ °C, and 110°C to show power rating where most users want to limit T_J in their application.

FIGURE 7. Temperature/power derating curve.



- 1. All devices are capable of operating at $\leq T_J$ specified on this curve. Any parallel line to this curve will intersect the appropriate power for the desired maximum T_J allowed.
- 2. Derate design curve constrained by the maximum junction temperature (T_J ≤ 175°C) and power rating specified. (Ssee 1.3 herein.)
- 3. Derate design curve chosen at $T_J \le 150$ °C, where the maximum temperature of electrical test is performed.
- 4. Derate design curves chosen at $T_J \le 125^{\circ}C$, and $110^{\circ}C$ to show power rating where most users want to limit T_J in their application.

FIGURE 8. Temperature/power derating curve.

THERMAL IMPEDANCE CURVE 1N6485 THROUGH 1N6491 AND 1N4460 THROUGH 1N4461

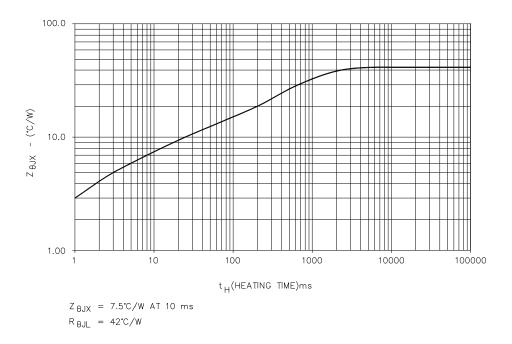


FIGURE 9. Thermal impedance curve for 1N6485 through 1N6491 and 1N4460 through 1N4461.

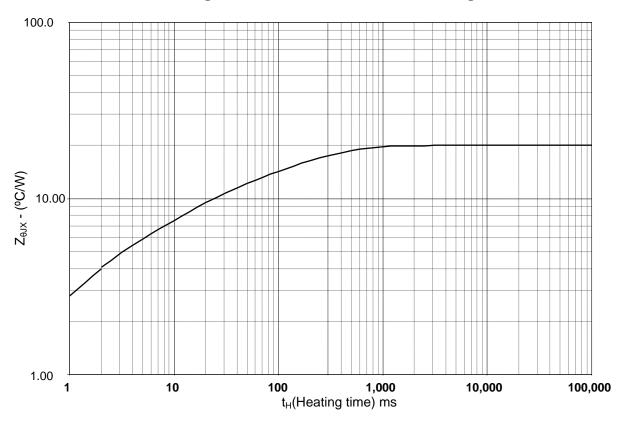
Thermal Impedance Curve 1N4462 through 1N4496 100.0 100.

FIGURE 10. Thermal impedance curve for 1N4462 through 1N4496.

 $Z_{\theta JX} = 5.7^{\circ} \text{C/W}$ at 10 ms

 $R_{\theta JL} = 42^{\circ} C/W$

Thermal Impedance Curve 1N6485US through 1N6491US and 1N4460US through 1N4461US

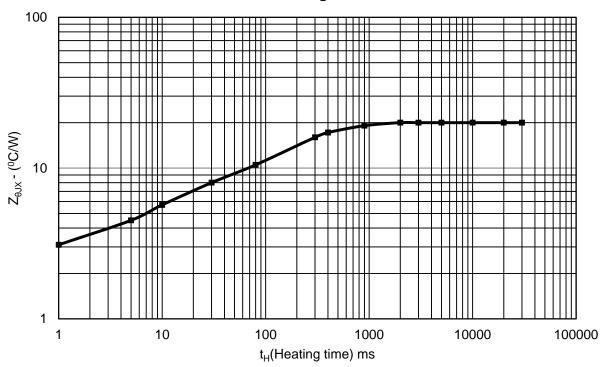


 $Z_{\theta JX} = 7.5^{\circ} \text{C/W}$ at 10 ms

 $R_{\theta JEC} = 20^{\circ} C/W$

FIGURE 11. Thermal impedance curve for 1N6485US through 1N6491US and 1N4460US through 1N4461US.

Thermal Impedance Curve 1N4462US through 1N4496US

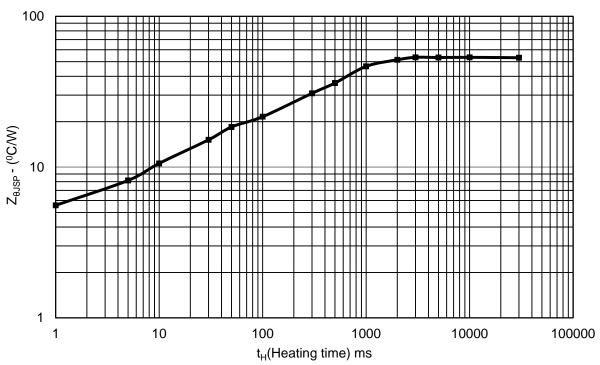


 $Z_{\theta JX} = 5.7^{\circ}$ C/W at 10 ms

 $R_{\theta JEC} = 20^{\circ} C/W$

FIGURE 12. Thermal impedance curve for 1N4462US through 1N4496US.

Thermal Impedance Curve 1N4462UM through 1N4496UM



 $Z_{\theta JSP}$ = 10.6 °C/W at 10 ms

 $R_{\theta JSP} = 56^{\circ} C/W$

NOTE:

1. Curve achieved using 4 in² (2,580 mm²) mounting pad of 2 ounce copper foil.

FIGURE 13. Thermal impedance curve for 1N4462UM through1N4496UM.

5. PACKAGING

5.1 <u>Packaging</u>. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When packaging of materiel is to be performed by DoD or in-house contractor personnel, these personnel need to contact the responsible packaging activity to ascertain packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activities within the Military Service or Defense Agency, or within the Military Service's system commands. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

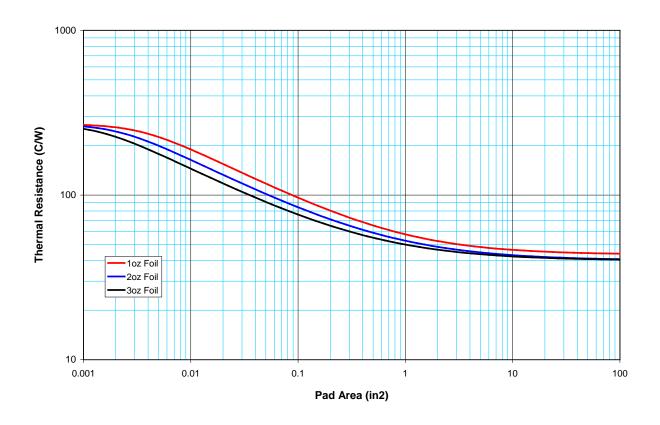
6. NOTES

(This section contains information of a general or explanatory nature that may be helpful, but is not mandatory. The notes specified in MIL-PRF-19500 are applicable to this specification.)

- 6.1 <u>Intended use</u>. Semiconductors conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.
- * 6.2 Acquisition requirements. Acquisition documents should specify the following:
 - a. Title, number, and date of this specification.
 - b. Packaging requirements (see 5.1).
 - c. Lead finish (see 3.4.2).
 - d. The complete PIN (see 1.5 and 6.5).
 - e. Surface mount designation if applicable.
- 6.3 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List (QML 19500) whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DLA Land and Maritime, VQE, P.O. Box 3990, Columbus, OH 43218-3990 or e-mail vqe.chief@dla.mil. An online listing of products qualified to this specification may be found in the Qualified Products Database (QPD) at https://assist.dla.mil.

6.4 Applications data.

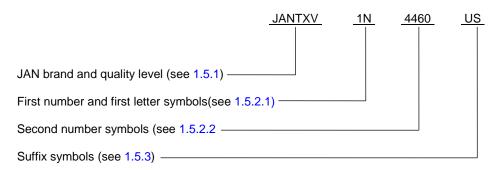
- 6.4.1 PCB (PCB1) mounting with FR4 material for only 0.6 W. For a printed board mounting example with FR4 base material where only 0.6 watts of power is used as shown on figure 6 with 200°C/W thermal resistance junction to ambient at a TJ of 175°C and ambient temperature of 55°C, the following steps guide the user in what the printed board copper mounting pad size will need to be in area for each pad with 1 ounce, 2 ounce, and 3 ounce copper. For axial-leaded, the lead length for mounting will be .187 inch (4.75 mm) or less from body to entry point on PCB surface.
 - a. Look up thermal resistance value of the required 200°C/W on the Y-axis using a thermal resistance versus copper mounting pad area plot on each of the three curves on figure 15 for different weights of copper foil and then intersect curve horizontally to get the answer. These curves assume still air and horizontal printed board position.
 - b. In this example, the copper mounting pad sizes for the different copper foil weights would be as follows:
 - (1) .0085 in² (5.48 mm²) for 1 ounce copper foil.
 - (2) .0050 in² (3.23 mm²) for 2 ounce copper foil.
 - (3) .0032 in² (2.06 mm²) for 3 ounce copper foil.
 - c. Add a conservative guard-band to the copper mounting pad size (larger) to keep T_J below 175°C.
- 6.4.2 PCB (PCB2) mounting with FR4 material for the full 1.5 W. For a printed board mounting example with FR4 base material where the full 1.5 watt power rating is used as shown on figure 7 with 80°C/W thermal resistance junction to ambient at a T_J of 175°C and ambient temperature of 55°C, the following steps guide the user in what the printed board copper mounting pad size will need to be in area for each pad with 1 ounce, 2 ounce, and 3 ounce copper. For axial-leaded, the lead length for mounting will be .187 inch (4.75 mm) or less from body to entry point on PCB surface.
 - a. Look up thermal resistance value of the required 80°C/W on the Y-axis using a thermal resistance versus copper mounting pad area plot on each of the three curves on figure 15 for different weights of copper foil and then intersect curve horizontally to get the answer. These curves assume still air and horizontal printed board position.
 - b. In this example the copper mounting pad sizes for the different copper foil weights would be as follows:
 - (1) .20 in² (129 mm²) for 1 ounce copper foil.
 - (2) .12 in² (77.4 mm²) for 2 ounce copper foil.
 - (3) .08 in² (51.6 mm²) for 3 ounce copper foil.
 - Add a conservative guard-band to the copper mounting pad size (larger) to keep T_J below 175°C.



1. See figure 13 for UM package.

FIGURE 14. Thermal resistance versus FR4 pad area still air, PCB horizontal (for each pad) with 1 oz copper (top curve), 2 oz copper (middle curve), and 3 oz copper (bottom curve).

* 6.5 <u>PIN construction examples</u>. The PIN for encapsulated devices are constructed using the following form.



* 6.6 <u>List of PINs</u>. The following is a list of possible PINs available on this specification sheet.

PINs for devices of the	PINs for devices of the	PINs for devices of the	PINs for devices of the
JAN1N4460	"TX" quality level JANTX1N4460	"TXV" quality level JANTXV1N4460	"S" quality level JANS1N4460
0			
JAN1N4460C	JANTX1N4460C	JANTXV1N4460C	JANS1N4460C
JAN1N4460CUS	JANTX1N4460CUS	JANTXV1N4460CUS	JANS1N4460CUS
JAN1N4460D	JANTX1N4460D	JANTXV1N4460D	JANS1N4460D
JAN1N4460DUS	JANTX1N4460DUS	JANTXV1N4460DUS	JANS1N4460DUS
JAN1N4460UM	JANTX1N4460UM	JANTXV1N4460UM	JANS1N4460UM
JAN1N4460US	JANTX1N4460US	JANTXV1N4460US	JANS1N4460US
JAN1N4461C	JANTX1N4461C	JANTXV1N4461C	JANS1N4461C
JAN1N4461CUS	JANTX1N4461CUS	JANTXV1N4461CUS	JANS1N4461CUS
JAN1N4461D	JANTX1N4461D	JANTXV1N4461D	JANS1N4461D
JAN1N4461DUS	JANTX1N4461DUS	JANTXV1N4461DUS	JANS1N4461DUS
JAN1N4461UM	JANTX1N4461UM	JANTXV1N4461UM	JANS1N4461UM
JAN1N4461US	JANTX1N4461US	JANTXV1N4461US	JANS1N4461US
JAN1N4462	JANTX1N4462	JANTXV1N4462	JANS1N4462
JAN1N4462C	JANTX1N4462C	JANTXV1N4462C	JANS1N4462C
JAN1N4462CUS	JANTX1N4462CUS	JANTXV1N4462CUS	JANS1N4462CUS
JAN1N4462D	JANTX1N4462D	JANTXV1N4462D	JANS1N4462D
JAN1N4462DUS	JANTX1N4462DUS	JANTXV1N4462DUS	JANS1N4462DUS
JAN1N4462UM	JANTX1N4462UM	JANTXV1N4462UM	JANS1N4462UM
JAN1N4462US	JANTX1N4462US	JANTXV1N4462US	JANS1N4462US
JAN1N4463	JANTX1N4463	JANTXV1N4463	JANS1N4463
JAN1N4463C	JANTX1N4463C	JANTXV1N4463C	JANS1N4463C
JAN1N4463CUS	JANTX1N4463CUS	JANTXV1N4463CUS	JANS1N4463CUS
JAN1N4463D	JANTX1N4463D	JANTXV1N4463D	JANS1N4463D
JAN1N4463DUS	JANTX1N4463DUS	JANTXV1N4463DUS	JANS1N4463DUS
JAN1N4463UM	JANTX1N4463UM	JANTXV1N4463UM	JANS1N4463UM
JAN1N4463US	JANTX1N4463US	JANTXV1N4463US	JANS1N4463US

10014014404	IANTX/ANIA 40 A	1451TXX (4514.40.4	100104014404
JAN1N4464	JANTX1N4464	JANTXV1N4464	JANS1N4464
JAN1N4464C	JANTX1N4464C	JANTXV1N4464C	JANS1N4464C
JAN1N4464CUS	JANTX1N4464CUS	JANTXV1N4464CUS	JANS1N4464CUS
JAN1N4464D	JANTX1N4464D	JANTXV1N4464D	JANS1N4464D
JAN1N4464DUS	JANTX1N4464DUS	JANTXV1N4464DUS	JANS1N4464DUS
JAN1N4464UM	JANTX1N4464UM	JANTXV1N4464UM	JANS1N4464UM
JAN1N4464US	JANTX1N4464US	JANTXV1N4464US	JANS1N4464US
JAN1N4465	JANTX1N4465	JANTXV1N4465	JANS1N4465
JAN1N4465C	JANTX1N4465C	JANTXV1N4465C	JANS1N4465C
JAN1N4465CUS	JANTX1N4465CUS	JANTXV1N4465CUS	JANS1N4465CUS
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JAN1N6485	JANTX1N6485	JANTXV1N6485	JANS1N6485
JAN1N6485C	JANTX1N6485C	JANTXV1N6485C	JANS1N6485C
JAN1N6485CUS	JANTX1N6485CUS	JANTXV1N6485CUS	JANS1N6485CUS
JAN1N6485D	JANTX1N6485D	JANTXV1N6485D	JANS1N6485D
JAN1N6485DUS	JANTX1N6485DUS	JANTXV1N6485DUS	JANS1N6485DUS
JAN1N6485US	JANTX1N6485US	JANTXV1N6485US	JANS1N6485US
JAN1N6486	JANTX1N6486	JANTXV1N6486	JANS1N6486
JAN1N6486C	JANTX1N6486C	JANTXV1N6486C	JANS1N6486C
JAN1N6486CUS	JANTX1N6486CUS	JANTXV1N6486CUS	JANS1N6486CUS
JAN1N6486D	JANTX1N6486D	JANTXV1N6486D	JANS1N6486D
JAN1N6486DUS	JANTX1N6486DUS	JANTXV1N6486DUS	JANS1N6486DUS
JAN1N6486US	JANTX1N6486US	JANTXV1N6486US	JANS1N6486US
JAN1N6487	JANTX1N6487	JANTXV1N6487	JANS1N6487
JAN1N6487C	JANTX1N6487C	JANTXV1N6487C	JANS1N6487C
JAN1N6487CUS	JANTX1N6487CUS	JANTXV1N6487CUS	JANS1N6487CUS
JAN1N6487D	JANTX1N6487D	JANTXV1N6487D	JANS1N6487D
JAN1N6487DUS	JANTX1N6487DUS	JANTXV1N6487DUS	JANS1N6487DUS
JAN1N6487US	JANTX1N6487US	JANTXV1N6487US	JANS1N6487US

* 6.6 List of PINs – continued.

JAN1N6488	JANTX1N6488	JANTXV1N6488	JANS1N6488
JAN1N6488C	JANTX1N6488C	JANTXV1N6488C	JANS1N6488C
JAN1N6488CUS	JANTX1N6488CUS	JANTXV1N6488CUS	JANS1N6488CUS
JAN1N6488D	JANTX1N6488D	JANTXV1N6488D	JANS1N6488D
JAN1N6488DUS	JANTX1N6488DUS	JANTXV1N6488DUS	JANS1N6488DUS
JAN1N6488US	JANTX1N6488US	JANTXV1N6488US	JANS1N6488US
JAN1N6489	JANTX1N6489	JANTXV1N6489	JANS1N6489
JAN1N6489C	JANTX1N6489C	JANTXV1N6489C	JANS1N6489C
JAN1N6489CUS	JANTX1N6489CUS	JANTXV1N6489CUS	JANS1N6489CUS
JAN1N6489D	JANTX1N6489D	JANTXV1N6489D	JANS1N6489D
JAN1N6489DUS	JANTX1N6489DUS	JANTXV1N6489DUS	JANS1N6489DUS
JAN1N6489US	JANTX1N6489US	JANTXV1N6489US	JANS1N6489US
JAN1N6490	JANTX1N6490	JANTXV1N6490	JANS1N6490
JAN1N6490C	JANTX1N6490C	JANTXV1N6490C	JANS1N6490C
JAN1N6490CUS	JANTX1N6490CUS	JANTXV1N6490CUS	JANS1N6490CUS
JAN1N6490D	JANTX1N6490D	JANTXV1N6490D	JANS1N6490D
JAN1N6490DUS	JANTX1N6490DUS	JANTXV1N6490DUS	JANS1N6490DUS
JAN1N6490US	JANTX1N6490US	JANTXV1N6490US	JANS1N6490US
JAN1N6491	JANTX1N6491	JANTXV1N6491	JANS1N6491
JAN1N6491C	JANTX1N6491C	JANTXV1N6491C	JANS1N6491C
JAN1N6491CUS	JANTX1N6491CUS	JANTXV1N6491CUS	JANS1N6491CUS
JAN1N6491D	JANTX1N6491D	JANTXV1N6491D	JANS1N6491D
JAN1N6491DUS	JANTX1N6491DUS	JANTXV1N6491DUS	JANS1N6491DUS
		JANTXV1N6491US	JANS1N6491US

6.7 <u>Changes from previous issue</u>. The margins of this specification are marked with astericks to indicate where changes from the previous issue were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the previous issue.

Custodians:

Army - CR Navy - EC Air Force - 85 NASA - NA

DLA - CC

Review activities:

Army - AR, MI, SM Navy - AS, MC Air Force - 19 Preparing activity: DLA - CC

(Project 5961-2015-030)

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